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What is claimed is:

- A method of wiring formation comprising the steps of:
 forming a feeder film partially on a substrate;
 forming on the substrate a plating base film such that
 the plating base film partially overlaps the feeder film;
 forming a plated wiring on the plating base film; and
 selectively removing at least a portion of the feeder
 film that is exposed from the plated wiring.
- 10 2. A method of wiring formation according to Claim 1, wherein the step of forming on the substrate a plating base film is performed using a physical film making process.
- 3. A method of wiring formation according to Claim 1,
 15 wherein the step of forming a plated wiring on the plating base film is performed using an electrolytic plating process.
 - 4. A method of wiring formation according to Claim 1, wherein the step of selectively removing at least a portion of the feeder film that is exposed from the plated wiring is performed using a wet etching process.
 - 5. A method of wiring formation according to Claim 1, wherein a width of a portion of the plating base film that is stacked on the feeder film is wider than the smallest wire width of the feeder film.
 - 6. A method of wiring formation according to Claim 1, wherein the plating base film comprises at least one of an adhesive layer and a diffusion preventive layer.

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7. A method of wiring formation comprising the steps of: forming a feeder film partially on a substrate;

forming on the substrate a resist pattern which has an opening defining a wiring forming area, such that a portion of the feeder film is exposed from the opening in the resist pattern;

forming a plating base film at least on the substrate in the opening;

forming a plated wiring on the plating base film in the 10 opening;

removing the resist pattern; and selectively removing at least a portion of the feeder film that is exposed from the plated wiring.

- 8. A method of wiring formation according to Claim 7, wherein the step of forming on the substrate a plating base film is performed using a physical film making process.
- 9. A method of wiring formation according to Claim 7,
 20 wherein the step of forming a plated wiring on the plating base film is performed using an electrolytic plating process.
 - 10. A method of wiring formation according to Claim 7, wherein the step of selectively removing at least a portion of the feeder film that is exposed from the plated wiring is performed using a wet etching process.
- 11. A method of wiring formation according to Claim 7, wherein a width of a portion of the plating base film that is stacked on the feeder film is wider than the smallest wire width of the feeder film.

12. A method of wiring formation according to Claim 7, wherein the plating base film comprises at least one of an adhesive layer and a diffusion preventive layer.

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13. A method of manufacturing an electronic component comprising the steps of:

providing a substrate;

forming a feeder film partially on the substrate;

forming on the substrate a plating base film by using a physical film making process such that the plating base film partially overlaps the feeder film;

forming a plated wiring on the plating base film using an electrolytic plating process; and

selectively removing at least a portion of the feeder film that is exposed from the plated wiring, using a wet etching process.

- 14. A method according to Claim 13, wherein a width of a portion of the plating base film that is stacked on the feeder film is wider than the smallest wire width of the feeder film.
- 15. A method according to Claim 13, wherein a width of a portion of the plating base film that is stacked on the feeder film is wider than the smallest wire width of the feeder film.
 - 16. A method according to Claim 13, wherein the plating base film comprises at least one of an adhesive layer and a diffusion preventive layer.

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17. A method of manufacturing an electronic component comprising the steps of:

providing a substrate;

forming a feeder film partially on a substrate;

forming on the substrate a resist pattern which has an opening defining a wiring forming area, such that a portion of the feeder film is exposed from the opening in the resist pattern;

forming a plating base film at least on the substrate in the opening using a physical film making process;

forming a plated wiring on the plating base film in the opening using an electrolytic plating process;

removing the resist pattern; and

selectively removing at least a portion of the feeder film that is exposed from the plated wiring, using a wet etching.

- 18. A method according to Claim 17, wherein a width of a portion of the plating base film that is stacked on the feeder film is wider than the smallest wire width of the feeder film.
- 19. A method according to Claim 17, wherein a width of a portion of the plating base film that is stacked on the feeder film is wider than the smallest wire width of the feeder film.
- 20. A method according to Claim 17, wherein the plating base film comprises at least one of an adhesive layer and a diffusion preventive layer.

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